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L25	l19 and l22	4	L25
L24	l19 and l21	11	L24
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| L20 | (712/200-219,225-227, 241-248)![CCLS] | 5783 | L20 |

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L19	L18 and (thread$3 or multi near1 thrread$3)	90	L19
L18	push$4 near25 pop$4 near25 stack near25 point$3	549	L18
L17	push$4 near25 pop$4 near25 stack near25 (sram or static) near25 point$3	0	L17

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L16	l3 and memor$4	1	L16
L15	L14 and (push or pop)	29	L15
L14	stack near5 sram	109	L14
L13	L12 and sram	0	L13
L12	5946487.pn.	1	L12
L11	L10 and sram	0	L11
L10	5968169.pn.	1	L10
L9	L8 and sram	0	L9
L8	3889243.pn.	1	L8
L7	L4 and ram$1	0	L7
L6	L4 and sram$1	0	L6
L5	L4 and sram	0	L5
L4	L3 and offset	1	L4
L3	5542070.pn.	1	L3
L2	associat$3 near8 pop near8 push	54	L2
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Source Code Analysis and Manipulation, 2004. Fourth IEEE International Workshop on
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Digital Object Identifier 10.1109/SCAM.2004.2

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Madan, B.B.; Phoha, S.; Trivedi, K.S.;
Information Technology: Coding and Computing, 2005. ITCC 2005. International Conference on
Volume 1, 4-6 April 2005 Page(s):656 - 661 Vol. 1
Digital Object Identifier 10.1109/ITCC.2005.260

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Stoltzfus, B.S.; Elizondo, J.M.; Savage, M.E.;
Plasma Science, 2004. ICOPS 2004. IEEE Conference Record - Abstracts. The 31st IEEE Internat
28 June-1 July 2004 Page(s):444
Digital Object Identifier 10.1109/PLASMA.2004.1340259

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Ramanathan, L.N.; Mitchell, D.;
Electronic Components and Technology Conference, 2000. 2000 Proceedings. 50th
21-24 May 2000 Page(s):837 - 843
Digital Object Identifier 10.1109/ECTC.2000.853258

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5-8 March 2003 Page(s):702 - 704

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7. **Development of an etchant for selectively etching $TiWN_x$ in the presence of electroplated 95**
Ramanathan, L.N.; Mitchell, D.;
Components and Packaging Technologies, IEEE Transactions on [see also Components, Packagir
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Volume 24, Issue 3, Sept. 2001 Page(s):425 - 430
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